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(54) GAIN AND OFFSET DIAGNOSIS OF ANALOG-TO-DIGITAL CONVERTERS IN SENSOR SIGNAL PATH

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(57)**ABSTRACT**

A sensor circuit, having a startup phase and an operation phase, includes: a sensor configured to generate a sensor signal based on a measured property, wherein the sensor signal has a frequency spectrum defined by a first frequency and a second frequency that is greater than the first frequency; a signal processing circuit including an analog-todigital converter (ADC) configured to convert the sensor signal into a digital sensor signal; and an offset diagnosis circuit. The offset diagnosis circuit includes: a low pass filter having a cutoff frequency less than the first frequency and configured to generate a filtered signal based on the digital sensor signal; an offset register configured to store a startup signal value of the filtered signal during the startup phase; and an offset comparator circuit configured to set a threshold range based on the startup signal value for use during the operation phase.

